

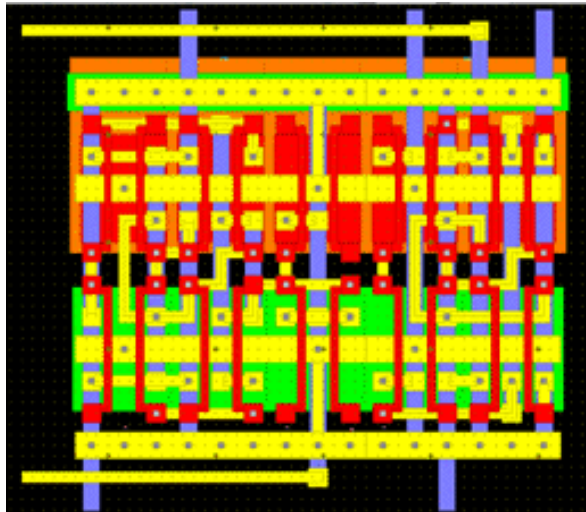
Hierarchical Layout Operations

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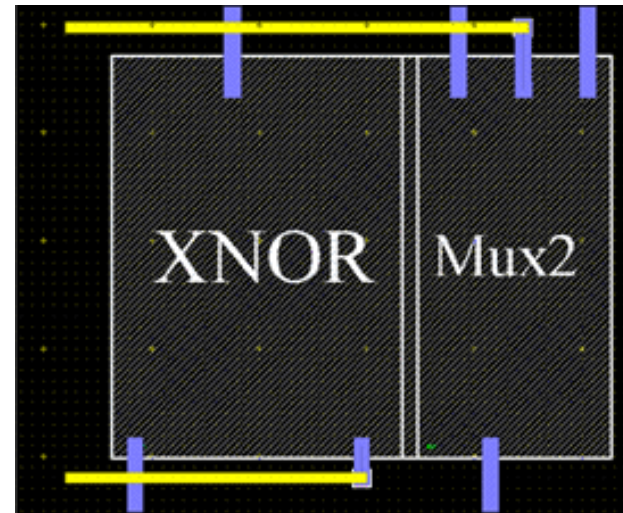
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Hierarchical vs. Flat Layout

Flat



Hierarchy



Why Hierarchy?

- Less memory
 - Same cell instantiated multiple times
- Less processing time
 - Repeated structure verified “once”
 - To determine which geometries are close enough for a DR violation → sorting
 - Chip with n polygons
 - Flat: $O(n \log (n))$
 - Hier on 2 cells: $2((n/2)\log(n/2)) + \text{cell interaction overhead}$

Why Hierarchy (cont'd)

- Better results in verification (designer perspective)
 - E.g. DRC : reporting a much smaller set of violations → easier debugging

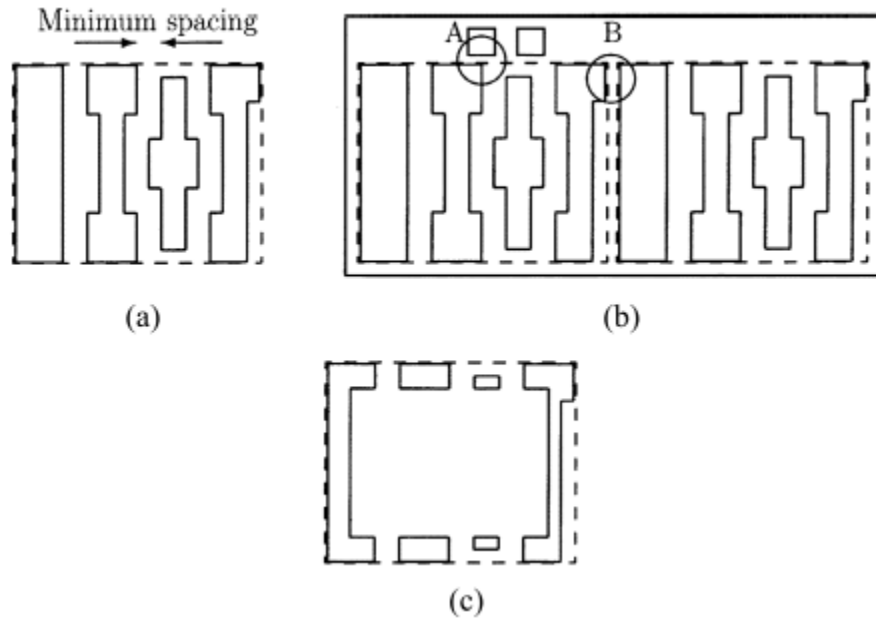
Challenges in Hierarchical Processing

- Cell neighborhood/instantiation affect results
 - Also Cells may overlap
 - Different orientations of cells
- Migration/Compaction and DP:
 - Multiple instances of same cell → different sets of constraints BUT ONE output cell
 - Working on **hierarchical** view → different results from working on **flat** view of same layout

Challenges in Hierarchical Processing (cont'd)

- Hierarchical DRC is NP-complete [2]

Example [2]



a: cell

b: hierarchical layout

c: Abstract of cell

Hierarchical Verification Flow

1. Check all leaf cells.
2. For each cell
 - build an abstract:
 - a (hopefully) simpler version of the cell that only contains features that are needed for checking cell interactions.
3. Start at hierarchy level 1 (from leaf)
4. Verify cells of current hier. level:
 - a. Substitute with cell abstracts
 - b. Run **flat** verification algorithm on resulting data
5. Prepare abstract for the next higher level
6. Repeat till top of hierarchy

References

- [1] Telle Whitney; “A Hierarchical Design Rule Checker”; M.Sc. Thesis, Caltech, 1981
- [2] Louis K. Scheffer; “Some Conditions Under Which Hierarchical Verification is $O(N)$ ”; TCAD; 2003
- [3] <http://www.semiwiki.com/forum/showwiki.php?title=Semi+Wiki:Design+Rule+Checking+DRC+Wiki>
- [4] “Hierarchical Layout Verification”; Todd J. Wagner, Intel; DAC; 1984